

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/572,940 | Applicant(s)/Patent Under Reexamination MITSUI ET AL. | |
| | Examiner MARK A. OSELE | Art Unit 1745 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-6,796,351 B1 | 09-2004 | Maeda, Tsuyoshi | 156/391 |
| * | B | US-6,698,489 B1 | 03-2004 | Shinozaki et al. | 156/574 |
| * | C | US-6,508,287 B1 | 01-2003 | Shinozaki et al. | 156/391 |
| * | D | US-6,098,685 A | 08-2000 | Maeda, Tsuyoshi | 156/391 |
| * | E | US-6,748,993 B1 | 06-2004 | Shinozaki et al. | 156/391 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.